P74

5th International Symposium of Gunma University Medical Innovation and
9th International Conference on Advanced Micro-Device Engineering
(**GUMI&AMDE 2018**)

ADC Histogram Test for Specific Codes

Yujie Zhao, Yuto Sasaki, Yuki Ozawa, Riho Aoki, Anna Kuwana, Haruo Kobayashi

Division of Electronics and Informatics, Gunma University, JAPAN

Background: Internet of Things (IoT)
Sensor interface analog circuit is a key.

Requirement: High reliability

Challenge:
Their production testing with high quality, low cost

Research target:
Short time testing of high resolution, low speed
analog-to-digital converter (ADC)

Our approach:
Consideration of ADC internal circuit.
Finding of error prone codes and careful testing.

We have developed its effective testing algorithms